

Notice of References Cited

Application/Control No.

09/836,711

Applicant(s)/Patent Under
Reexamination
WATANABE ET AL.

Examiner

Brian P. Egan

Art Unit

1772

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,827,445	10-1998	Yoshida et al.	252/62.54
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	WO 00/19792	04-2000	PCT	Nakahoshi et al.	Translation Provided
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.